

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/766,776	DOAN, JONATHAN	
		Examiner	Art Unit	Page 1 of 1
		Eric B. Chen	1765	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0040675	11-2001	True et al.	355/77
*	B	US-5,057,187	10-1991	Shinagawa et al.	438/725
*	C	US-6,804,039	10-2004	Doan et al.	359/291
*	D	US-6,180,543	01-2001	Yu et al.	438/787
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wolf et al., Silicon Processing for the VLSI Era, 1986, Lattice Press, Vol. 1, pp. 179, 180, 200-201, 209-211, 216-219, 230-232, 374, 564, 570.
	V	Callister, Materials Science and Engineering, 1997, John Wiley & Sons, 4th ed., pp. 592, 593, 601.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.